10/589681 MFS ROSCIPLATE 13 AUG 2006

SHIGA7.054APC PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant

Ogata et al.

Appl. No.

U.S. National Phase of

PCT/JP2005/001228

Filed

Herewith

For

POLYMER COMPOUND,

PHOTORESIST COMPOSITION INCLUDING THE POLYMER COMPOUND, AND RESIST PATTERN FORMATION

METHOD

Examiner

Unassigned

Group Art Unit

Unknown

CERTIFICATE OF MAILING

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first-class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on

August 16, 2006

(Date)

Neil S. Bartfeld, Ph.D., Reg. No. 39,90

PRELIMINARY AMENDMENT

Mail Stop PCT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Prior to examination of the above-referenced application, please enter the following amendments:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims begin on page 3 of this paper.

Remarks begin on page 8 of this paper.